

<b>Notice of References Cited</b>	Application/Control No. 10/758,928		Applicant(s)/Patent Under Reexamination LEE, JAE-CHANG	
	Examiner William H. Rodriguez		Art Unit 3746	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,532,731	03-2003	Springer, Gaylen	60/226.1
*	B	US-3,374,630	03-1968	DAVISON WILLIAM R; et. al.	60/226.1
*	C	US-2005/0229586	10-2005	Whurr, John R.	060/226.1
*	D	US-2003/0177769	09-2003	Graves et al.	60/752
*	E	US-2003/0070418	04-2003	Eiler et al.	60/262
*	F	US-2002/0134070	09-2002	Orlando et al.	60/204
*	G	US-2002/0026787	03-2002	Bregentzer, Daniel	60/226.1
*	H	US-6,584,778	07-2003	Griffiths et al.	60/782
*	I	US-6,553,765	04-2003	Bregentzer, Daniel	60/723
*	J	US-6,378,293	04-2002	Care et al.	60/226.1
*	K	US-4,631,914	12-1986	Hines, William R.	60/775
*	L	US-4,569,199	02-1986	Klees et al.	60/226.1
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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